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Pages 1-471

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TABLE OF CONTENTS

SESSION 6 – DESIGN AND OPTIMIZATION OF NANOCIRCUITS

SESSION 7 – PANEL

SESSION 8 – SPECIAL SESSION: DAWN OF THE 22NM DESIGN ERA – YES WE CAN!

SESSION 9 – STATISTICAL METHODS IN STATIC TIMING ANALYSIS

SESSION 10 – PROFILING, TEST AND DEBUG OF EMBEDDED SYSTEMS

SESSION 11 – LOW-POWER DESIGN AND ANALYSIS TECHNIQUES

SESSION 12 – DESIGN INTEGRITY CHALLENGES

SESSION 13 – PANEL

SESSION 14 – SPECIAL SESSION: VERIFYING AN SOC MONSTER: WHOSE JOB IS IT ANYWAY?

SESSION 15 – TIMING SIMULATION: OPTIMIZED EMBEDDED SOFTWARE AND MPSOCS

SESSION 16 – ADVANCES IN EMBEDDED SYSTEM MODELING AND OPTIMIZATION

SESSION 17 – INTERCONNECT OPTIMIZATION FOR EMERGING TECHNOLOGIES

SESSION 18 – DESIGN FLEXIBILITY: BEND IT, SHAPE IT, ANYWAY YOU WANT IT!

SESSION 19 – PANEL

SESSION 20 – SPECIAL SESSION: EMERGING TECHNOLOGIES: BLUE-SKY RESEARCH OR CMOS REPLACEMENT?

SESSION 21 – ROUTING: FROM CHIP TO PACKAGE

SESSION 22 – SPEED PATH IDENTIFICATION AND SILICON DEBUG

SESSION 23 – ANALOG/RF SIMULATION AND STATISTICAL MODELING

SESSION 24 – RECENT ADVANCES IN TIMING, ECO AND LOGIC OPTIMIZATION

SESSION 25 – PANEL

SESSION 26 – SPECIAL SESSION: COMPUTATION IN THE POST-TURING ERA

SESSION 27 – ADVANCES IN PHYSICAL SYNTHESIS

SESSION 28 – JUMPING THE HIGH-LEVEL VERIFICATION HURDLE

SESSION 29 – THERMAL OPTIMIZATION

SESSION 30 – NOVEL TECHNIQUES TO MINIMIZE CIRCUIT FAILURE

SESSION 31 – PANEL

SESSION 32 – SPECIAL SESSION: MULTICORE COMPUTING AND EDA

SESSION 33 – LAYOUT-BASED VARIABILITY MODELING AND OPTIMIZATION

SESSION 34 – ADVANCES IN CORE VERIFICATION TECHNIQUES

SESSION 35 – FUTURE INTERCONNECT TECHNOLOGIES: HOW DO ON-CHIP NETWORKS EVOLVE?

SESSION 36 – ROBUST ANALOG SYSTEM DESIGN

SESSION 37 – SPECIAL SESSION: WACI: WILD AND CRAZY IDEAS

SESSION 38 – SPECIAL SESSION: THE TOOL SHOWS THAT MY DESIGN IS WRONG, BUT WHERE IS THE BUG?

SESSION 39 – EMBEDDED SYSTEM DESIGN FOR LOW-POWER

SESSION 40 – HARDWARE AUTHENTICATION, CHARACTERIZATION AND TRUSTED DESIGN

SESSION 41 – TARGETED TEST AND DIAGNOSIS

SESSION 42 – CHALLENGES OF MEMORY-AWARE DESIGN FOR EMBEDDED SYSTEMS

SESSION 43 – PANEL

SESSION 44 – PARASITIC EXTRACTION IN THE FACE OF PROCESS VARIABILITY

SESSION 45 – SCHEDULING, ALLOCATION AND RELIABILITY

SESSION 46 – NETWORK-ON-CHIP ADVANCES FOR POWER, RELIABILITY AND THE MEMORY BOTTLENECK

SESSION 47 – LEVERAGING PARALLELISM IN FPGAS AND MULTICORE SYSTEMS

SESSION 48 – SPACE AND TIME MANAGEMENT IN EMBEDDED APPLICATIONS

SESSION 49 – PANEL

SESSION 50 – SPECIAL SESSION: TECHNOLOGIES FOR GREEN DATA CENTERS

SESSION 51 – HOW TO IMPROVE YOUR MEMORY

SESSION 52 – SCHEDULING IN TIME AND SPACE

SESSION 53 – HEURISTIC APPROACHES TO HARDWARE OPTIMIZATION

SESSION 54 – MODEL ORDER REDUCTION TECHNIQUES AND APPLICATIONS